

Application/Control No.	Applicant(s)/Patent under Reexamination
10/009,239	BAE ET AL.
Examiner	Art Unit
Duy M. Dang	2624

SEARCHED					
Subclass	Date	Examiner			
128 130-133 232-233	7/7/2006	DD }			
240 244					
305					
4 8					
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204	V	V			
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	Subclass 128 130-133 232-233 240 244 305 4 8 3	Subclass Date 128 130-133 7/7/2006 232-233 240 244 305 4 8 3 3			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (uspto, pgpub, derwent, jpo, epo) see printouts	7/7/2006	DD
Inventor search (east), see printouts		
IEEE search, see printout		
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